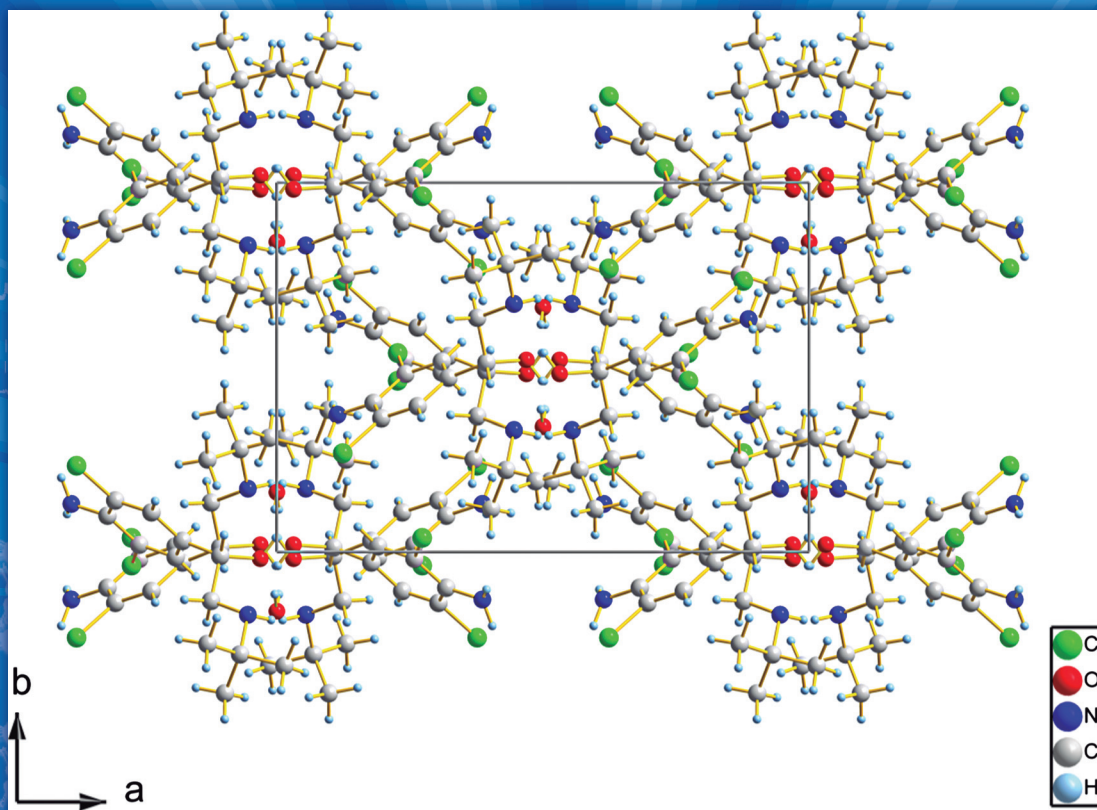


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On the Cover: A view down the c-axis of the structure of clenbuterol \cdot 0.5H₂O (Courtesy of R. Toro, J. Bruno-Colmenarez, G. Diaz de Delgado, and J. M. Delgado).

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